

4AM17

Silicon N/P Channel MOS FET
High Speed Power Switching

HITACHI

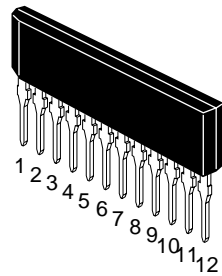
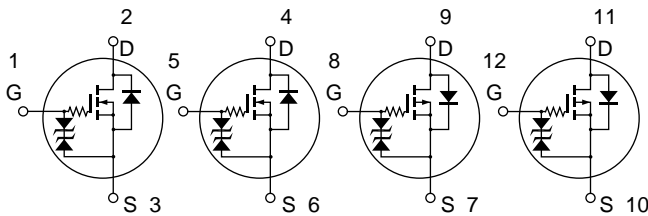
ADE-208-729 (Z)
1st. Edition
February 1999

Features

- Low on-resistance
N Channel: $R_{DS(on)} \leq 0.17 \Omega$, $V_{GS} = 10 \text{ V}$, $I_D = 4 \text{ A}$
P Channel: $R_{DS(on)} \leq 0.2 \Omega$, $V_{GS} = -10 \text{ V}$, $I_D = -4 \text{ A}$
- 4 V gate drive devices.
- High density mounting

Outline

SP-12



1, 5, 8, 12. Gate
2, 4, 9, 11. Drain
3, 6, 7, 10. Source

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Item	Symbol	Ratings		Unit
		Nch	Pch	
Drain to source voltage	V_{DSS}	60	-60	V
Gate to source voltage	V_{GSS}	± 20	± 20	V
Drain current	I_D	8	-8	A
Drain peak current	$I_{D(pulse)}^{Note1}$	32	-32	A
Body-drain diode reverse drain current	I_{DR}	8	-8	A
Channel dissipation	$Pch (T_c = 25^\circ\text{C})^{Note2}$		28	W
Channel dissipation	Pch^{Note2}		4.0	W
Channel temperature	Tch		150	$^\circ\text{C}$
Storage temperature	$Tstg$		-55 to +150	$^\circ\text{C}$

Note: 1. $PW \leq 10 \mu\text{s}$, duty cycle $\leq 1\%$
2. 4 devices operation

Electrical Characteristics (Ta = 25°C)

(N Channel)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	60	—	—	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	± 20	—	—	V	$I_G = \pm 100 \mu\text{A}, V_{DS} = 0$
Gate to source leak current	I_{GSS}	—	—	± 10	μA	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I_{DSS}	—	—	250	μA	$V_{DS} = 50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	1.0	—	2.5	V	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$
Static drain to source on state resistance	$R_{DS(on)}$	—	0.13	0.17	Ω	$I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}$ ^{Note3}
	$R_{DS(on)}$	—	0.19	0.24	Ω	$I_D = 4 \text{ A}, V_{GS} = 4 \text{ V}$ ^{Note3}
Forward transfer admittance	$ y_{fs} $	3.5	5.5	—	S	$I_D = 4 \text{ A}, V_{DS} = 10 \text{ V}$ ^{Note3}
Input capacitance	Ciss	—	33	—	pF	$V_{DS} = 10 \text{ V}$
Output capacitance	Coss	—	220	—	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	—	5.2	—	pF	$f = 1 \text{ MHz}$
Gate series resistance	Rg	—	1.5	—	k Ω	$V_{DS} = 10 \text{ V}, V_{GS} = 0$ $f = 1 \text{ MHz}$
Turn-on delay time	$t_{d(on)}$	—	0.15	—	ns	$V_{GS} = 10 \text{ V}, I_D = 4 \text{ A}$
Rise time	t_r	—	0.5	—	ns	$R_L = 7.5 \Omega$
Turn-off delay time	$t_{d(off)}$	—	3.2	—	ns	
Fall time	t_f	—	1.4	—	ns	
Body-drain diode forward voltage	V_{DF}	—	1.5	—	V	$I_F = 8 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t_{rr}	—	850	—	ns	$I_F = 8 \text{ A}, V_{GS} = 0$ $di_F/dt = 50 \text{ A}/\mu\text{s}$

Note: 3. Pulse test

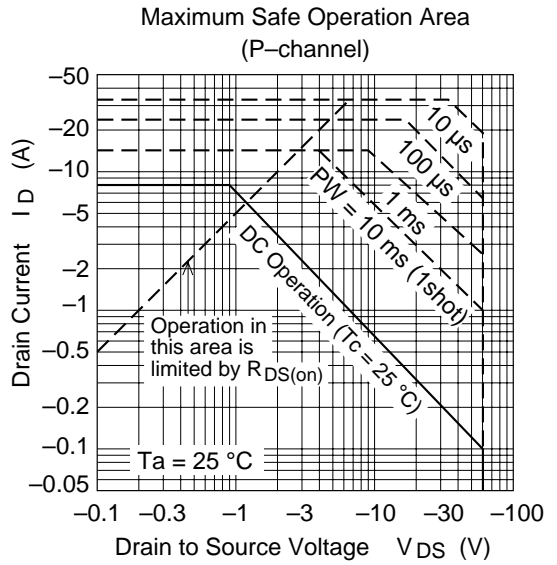
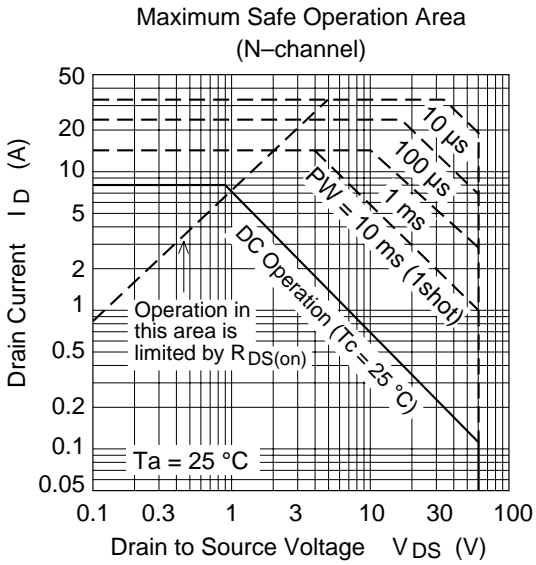
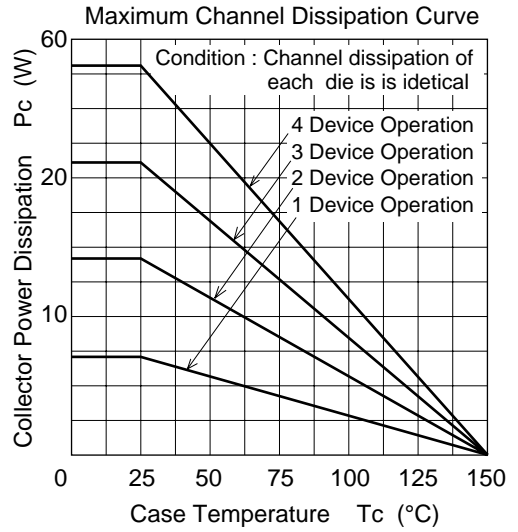
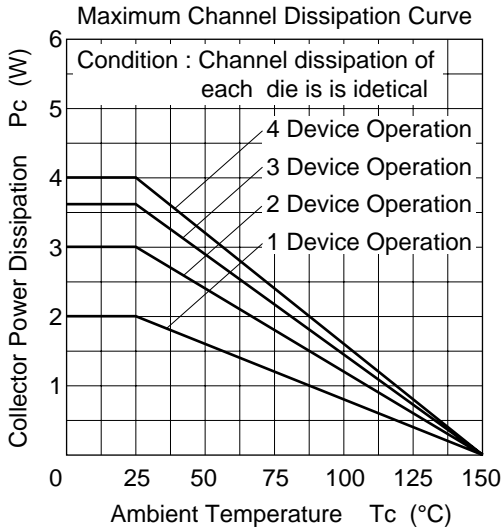
4AM17

(P Channel)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	-60	—	—	V	$I_D = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	± 20	—	—	V	$I_G = \pm 100 \mu\text{A}, V_{DS} = 0$
Gate to source leak current	I_{GSS}	—	—	± 10	μA	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I_{DSS}	—	—	-250	μA	$V_{DS} = -50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	-1.0	—	-2.5	V	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$
Static drain to source on state resistance	$R_{DS(on)}$	—	0.15	0.2	Ω	$I_D = -4 \text{ A}, V_{GS} = -10 \text{ V}$ ^{Note3}
	$R_{DS(on)}$	—	0.2	0.27	Ω	$I_D = -4 \text{ A}, V_{GS} = -4 \text{ V}$ ^{Note3}
Forward transfer admittance	$ y_{fs} $	3.5	6.0	—	S	$I_D = -4 \text{ A}, V_{DS} = -10 \text{ V}$ ^{Note3}
Input capacitance	Ciss	—	17	—	pF	$V_{DS} = -10 \text{ V}$
Output capacitance	Coss	—	460	—	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	—	1.2	—	pF	$f = 1 \text{ MHz}$
Gate series resistance	Rg	—	3.2	—	k Ω	$V_{DS} = 0, V_{GS} = 0 f = 1 \text{ MHz}$
Turn-on delay time	$t_{d(on)}$	—	0.6	—	ns	$V_{GS} = -10 \text{ V}, I_D = -4 \text{ A}$
Rise time	t_r	—	2.1	—	ns	$R_L = 7.5 \Omega$
Turn-off delay time	$t_{d(off)}$	—	12	—	ns	
Fall time	t_f	—	5.8	—	ns	
Body-drain diode forward voltage	V_{DF}	—	-1.2	—	V	$I_F = -8 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t_{rr}	—	2.5	—	ns	$I_F = -8 \text{ A}, V_{GS} = 0$ $diF/dt = 50 \text{ A}/\mu\text{s}$

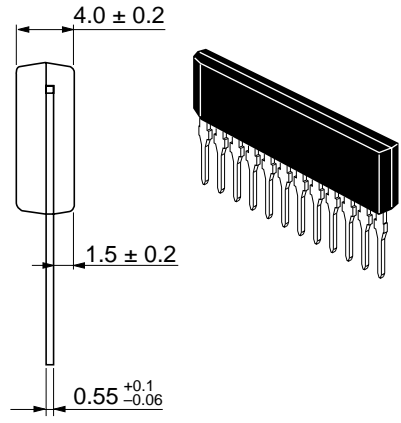
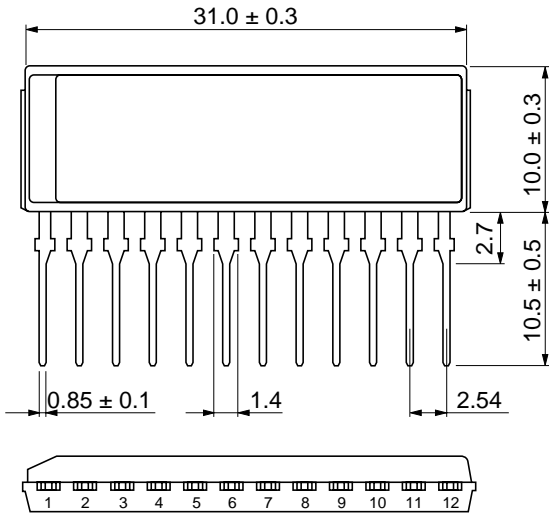
Note: 3. Pulse test

Main Characteristics



Package Dimensions

Unit: mm



Hitachi Code	SP-12
JEDEC	—
EIAJ	—

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Hitachi, Ltd.

Semiconductor & Integrated Circuits.
Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan
Tel: Tokyo (03) 3270-2111 Fax: (03) 3270-5109

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For further information write to:

Hitachi Semiconductor
(America) Inc.
179 East Tasman Drive,
San Jose, CA 95134
Tel: <1> (408) 433-1990
Fax: <1> (408) 433-0223

Hitachi Europe GmbH
Electronic components Group
Dornacher Straße 3
D-85622 Feldkirchen, Munich
Germany
Tel: <49> (89) 9 9180-0
Fax: <49> (89) 9 29 30 00

Hitachi Europe Ltd.
Electronic Components Group.
Whitebrook Park
Lower Cookham Road
Maidenhead
Berkshire SL6 8YA, United Kingdom
Tel: <44> (1628) 585000
Fax: <44> (1628) 778322

Hitachi Asia Pte. Ltd.
16 Collyer Quay #20-00
Hitachi Tower
Singapore 049318
Tel: 535-2100
Fax: 535-1533

Hitachi Asia Ltd.
Taipei Branch Office
3F, Hung Kuo Building, No.167,
Tun-Hwa North Road, Taipei (105)
Tel: <886> (2) 2718-3666
Fax: <886> (2) 2718-8180

Hitachi Asia (Hong Kong) Ltd.
Group III (Electronic Components)
7/F., North Tower, World Finance Centre,
Harbour City, Canton Road, Tsim Sha Tsui,
Kowloon, Hong Kong
Tel: <852> (2) 735 9218
Fax: <852> (2) 730 0281
Telex: 40815 HITEC HX

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